

Search Notes

Application/Control No.

10/715,464

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

TAKABAYASHI ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	102-105 9,10,100	10/12/2005	SWH
427	508,511	10/12/2005	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR